

Date	User	Film	Recipe	Dep.time	Thickness	JAW EC-400 (Woolam S. E.)			Avg Index	Index+1%	Index -1%	Avg.dep. rate				HF e.r.	Stress	Avg. Stress	Avg+10%	Avg-10%	LPD (light point defects)		Comment	Mike Silva
						Index @ 632.8nm	Index @ 1550nm	Index @ 632.8nm				(nm/min)	(nm/min)	(nm/min)	(nm/min)						(nm/min)	LPD before deposition		
01/01/14	User	SiO2	1_SiO2Dep	9sec	(A)																			
<b>Oxide</b>																								
01/09/14	Bijja	SiO2	Bijja_1_SiO2_dep	900	786.01	1.484	1.474	1.487	1.502	1.472	5.24	5.57	6.12	5.01	-367.80	-386.64	-425.30	-347.97	57	318	Not many particles			
01/31/14	Bijja	SiO2	Bijja_1_SiO2_dep	900	900.81	1.491	1.496	1.487	1.502	1.472	6.01	5.57	6.12	5.01	415.4	-405.46	-386.64	-425.30	-347.97			LPD not done		
03/19/14	Bijja	SiO2	Bijja_1_SiO2_dep	900	817.71	1.487	1.481	1.487	1.502	1.472	5.45	5.57	6.12	5.01	To do!	-386.65	-386.64	-425.30	-347.97	106	485	Not many particles		

Avg. Thickness	834.84	Avg. Dep. Rate	5.57	Avg HF e.r.	
Avg. Index	1.487	Avg. Stress	-386.64		
Avg+1%	1.502	Avg+10%	-425.30		
Avg-1%	1.472	Avg-10%	-347.97		

